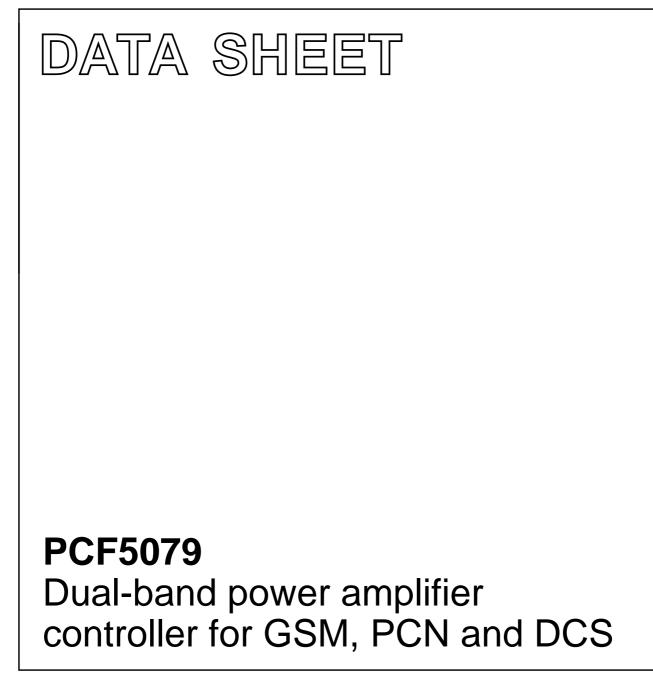
INTEGRATED CIRCUITS



Product specification File under Integrated Circuits, IC17 2001 Nov 21



Product specification

Dual-band power amplifier controller for GSM, PCN and DCS

PCF5079

CONTEN	ITS	13	PACKAGE OUTLINES
1	FEATURES	14	SOLDERING (TSSOP10)
2	APPLICATIONS	14.1	Introduction to soldering surface mount packages
3	GENERAL DESCRIPTION	14.2	Reflow soldering
4	QUICK REFERENCE DATA	14.3	Wave soldering
5	BLOCK DIAGRAM	14.4	Manual soldering
6	PINNING	14.5	Suitability of surface mount IC packages for wave and reflow soldering methods
6.1	Pin description	15	SOLDERING (HVSON10)
6.2	Pin configurations	15.1	Soldering information
7	FUNCTIONAL DESCRIPTION	15.2	PCB design guidelines
7.1	General	15.2.1	Perimeter pad design
7.2	Power-up mode	15.2.2	Thermal pad and via design
7.3 7.4	OP4 (integrator)	15.2.3	Stencil design for perimeter pads
7.4 7.5	Start-up and initial conditions Home position voltage	15.2.4 15.2.5	Stencil design for thermal pads Stencil thickness
7.6	End of burst		
7.7	Considerations for ramp-down	16	DATA SHEET STATUS
7.8	Configurations	17	DEFINITIONS
7.9	Summary of current and voltage definitions	18	DISCLAIMERS
7.10	Timing		
8	LIMITING VALUES		
9	ELECTROSTATIC DISCHARGE (ESD)		
10	DC CHARACTERISTICS		
11	OPERATING CHARACTERISTICS		
12	APPLICATION INFORMATION		
12.1	Ramp control		
12.2	PA protection against mismatch		
12.3	Detected voltage measurement		

12.4 Application examples

2001 Nov 21

PCF5079

1 FEATURES

- Compatible with baseband interface family PCF5073x
- Two power sensor inputs
- Temperature compensation of sensor signal
- Active filter for Digital-to-Analog Converter (DAC) input
- Power Amplifier (PA) protection against mismatching
- Bias current source for detector diodes
- Generation of pre-bias level for PA at start of burst (home position)
- Compatible with a wide range of silicon PAs
- Compatible with multislot class 12
- Dual output with internal switch
- Two different transfer functions
- Possibility to adapt dynamic transfer functions
- Very small outline package (3 × 3 mm).

QUICK REFERENCE DATA

4

2 APPLICATIONS

- Global System for Mobile communication (GSM)
- Personal Communications Network (PCN) systems.

3 GENERAL DESCRIPTION

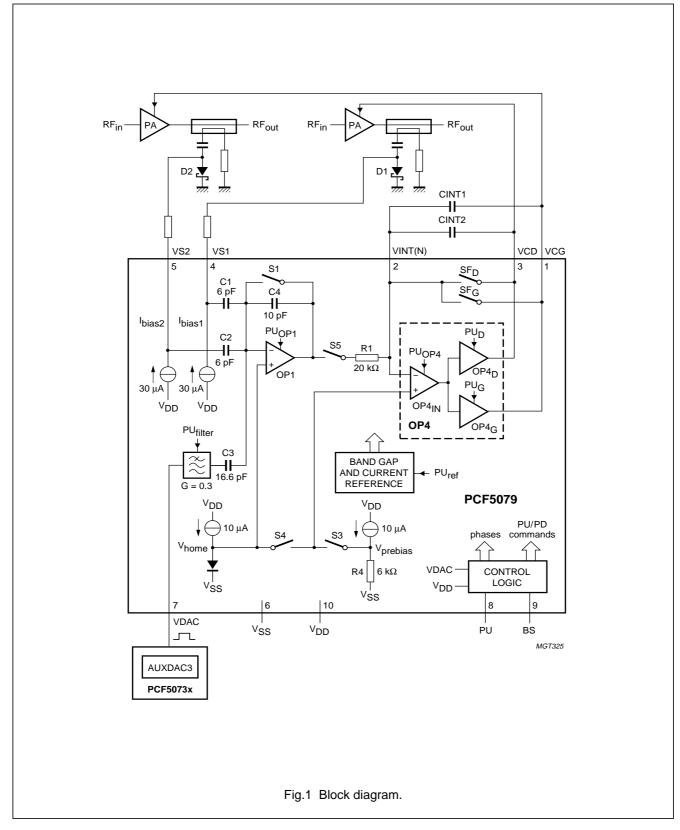
This CMOS device integrates an amplifier for the detected RF voltage from the sensor, an integrator and an active filter to build a PA control loop for cellular systems with a small number of passive components.

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V _{DD}	supply voltage	2.5	3.6	5.0	V
I _{DD(tot)}	total supply current	—	_	10	mA
T _{amb}	ambient temperature	-40	_	+85	°C

ORDERING INFORMATION

	TYPE NUMBER PACKAGE				
	NAME	DESCRIPTION	VERSION		
PCF5079T/C/1	TSSOP10	plastic thin shrink small outline package; 10 leads; body width 3 mm	SOT552-1		
PCF5079HK/C/1	HVSON10	plastic, heatsink very thin small outline package; no leads; 10 terminals; body $3 \times 3 \times 0.90$ mm	SOT650-1		

5 BLOCK DIAGRAM



PCF5079

6 PINNING

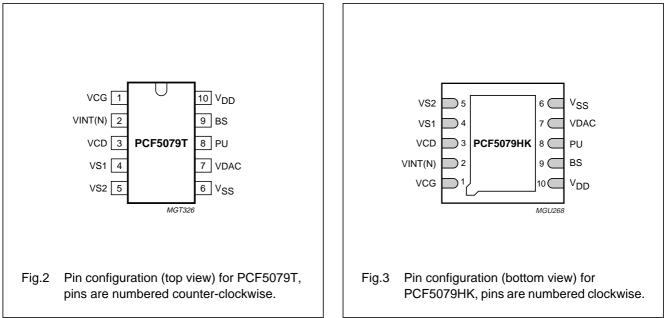
6.1 Pin description

SYMBOL	PIN	TYPE ⁽¹⁾	DESCRIPTION
VCG	1	O and A	PA control voltage output (GSM)
VINT(N)	2	I and A	negative integrator input
VCD	3	O and A	PA control voltage (DCS)
VS1	4	I/O and A	sensor signal input 1
VS2	5	I/O and A	sensor signal input 2
V _{SS}	6	G	reference ground
VDAC	7	I and A	DAC input voltage
PU	8	I and D	power-up input
BS	9	I and D	band selection input
V _{DD}	10	Р	positive supply voltage

Note

1. O = output, I = input, I/O = input/output, A = analog, D = digital, P = power supply and G = ground

6.2 Pin configurations



PCF5079

7 FUNCTIONAL DESCRIPTION

7.1 General

The PCF5079 contains an integrated amplifier for the detected RF voltage from the sensor, an integrator and an active filter to build up a PA control loop for cellular systems with a small number of passive components suitable for dual-band applications. The active band can be selected by means of the dedicated input BS.

The sensor amplifier can amplify signals from an RF power detector in a range of less than -20 to +15 dBm. This can comply to the PA output power range of GSM900/1800/1900 systems when, for example, a directional coupler with 20 dB attenuation is used for GSM900 and a directional coupler with 18 dB attenuation is used for GSM1800.

The external Schottky diodes for power detection (sensor) are biased by an integrated current source of $30 \ \mu$ A. Variations of the forward voltage with temperature have no influence on the measured signal because they are cancelled by the switched capacitor amplifier OP1.

An external DAC with at least 10-bit resolution (for example, AUXDAC3 of baseband interface family PCF5073x) is necessary to control the loop.

An integrated active filter smooths the voltage steps of the DAC during ramp-up and ramp-down.

The operation principle is the same, independently of the selected standard. The DAC signal and the sensor signal are added by amplifier OP1. The voltage difference of both signals is integrated by operational amplifier OP4 dedicated to the selected standard, which delivers the PA control voltage on an external capacitance, CINT1 or or CINT2, between pins VINT(N) and VCD or VCG, respectively. The shape of the rising and falling power burst edges can be determined by means of the DAC voltage.

7.2 Power-up mode

The device includes a power-up input (pin PU) to switch the IC on during time slots that are used in TDMA systems, and to switch the IC off during the unused slots to reduce current consumption.

7.3 OP4 (integrator)

The operational amplifier OP4 (integrator) consists of a shared input stage, $OP4_{IN}$ and a dedicated output driver for each standard, $OP4_G$ and $OP4_D$. Depending on the status of input BS, one driver is active and the other is kept in power-down mode during active time slots.

7.4 Start-up and initial conditions

The PCF5079 is designed to operate in bursts, as required in TDMA systems. Referring to Fig.4, for each time slot to be transmitted the PCF5079 must be enabled by setting signal PU to logic 1. Once pin PU is active, BS is taken into account to allow correct initialisation of switches S1, SF_D, SF_G, S3, S4 and S5, and of the configuration signals PU_G and PU_D.

The feedback switch across the unused driver is kept open and the output voltage from the unused driver is tied to V_{SS} to maintain the off state of the unused PA.

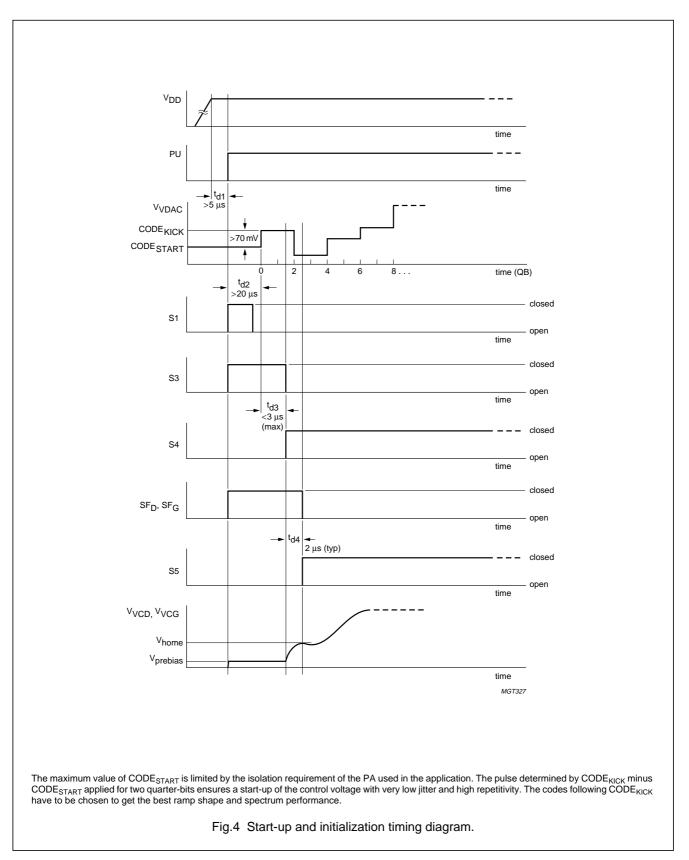
When pin PU is set to logic 1, at least 5 μ s after V_{DD} has reached its final value, switches S1, the appropriate switch SF_D or SF_G and S3 are closed, and switches S4 and S5 are opened. Because switch S1 is closed, the forward voltage of Schottky diodes D1 and D2 is sampled on capacitors C1 and C2 respectively.

Moreover, the control voltage on pin VCD or VCG is initially forced to be at the pre-bias voltage because the appropriate switch SF_D or SF_G and S3 are closed, and S4 is opened.

After a fixed time, defined on-chip, switch S1 is opened and the circuit is ready.

Once switch S1 is open, a ramp signal applied at pin VDAC (at least 20 µs after the transition of pin PU from logic 0 to logic 1) with an amplitude of at least 70 mV, from CODE_{START} to CODE_{KICK}, determines the opening of switch S3 and closing of switch S4 on the home voltage, with a delay of 3 µs maximum with respect to the ramp. After switch S3 opens (in a fixed amount of time), the control voltage on pin VCD or pin VCG rises to the home position to bias the PA to the beginning of the active range of its control curve. During this time (typically 2 µs), the appropriate switch SF_D or SF_G remains closed. When the appropriate switch SF_D or SF_G is opened, switch S5 is closed, allowing the transfer of any signal coming from amplifier OP1. After this preset, the control voltage is free to increase according to the control loop if the RF input is enabled (see Fig.12).

For higher DAC ramp steps, the delay of switch S3 opening (S4 closing) is reduced while the delay between switch SF_D (SF_G) opening with respect to S3 opening (S4 closing) remains unchanged.



7.5 Home position voltage

Internally, a forward voltage of an on-chip silicon diode is provided as a default home position. This voltage matches the requirements at the control input of most PAs and exhibits the same temperature coefficient.

7.6 End of burst

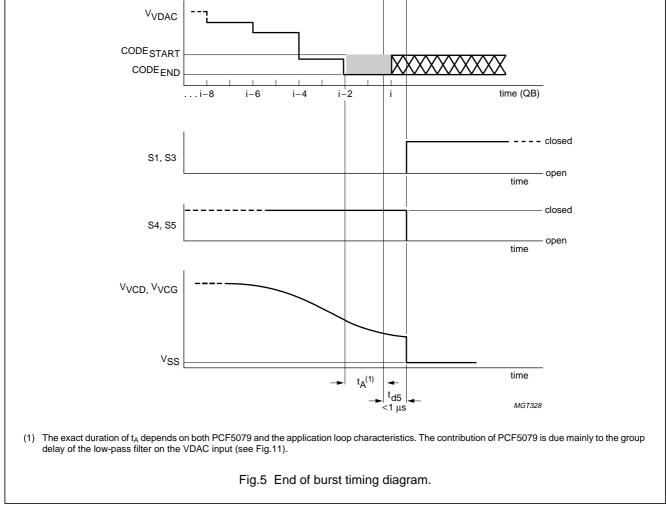
The ramp-down should drive the PA from conduction to shut off in a controlled way (see Fig.5). To get this result, correct DAC programming is required, so that the last code of the DAC ramp-down (CODE_{END}) is lower than the initial code of the ramp-up (CODE_{START}). In this way, the energy corresponding to the difference between start and end

ΡU

codes, applied for a certain number of Quarter-Bits (QB), is used to balance the energy stored in the summing node during the time interval between the start of control voltage on pin VCD or VCG ramping-up and the feedback of a detected ramp to the sensor input. Also a very slow ramp-down is avoided when the PA switches off and the loop gain becomes zero.

The amount of energy required at the end of the ramp-down depends on the overall loop gain and on the time needed to reach PA conduction from the home position. At the end of a burst, when pin PU is set to logic 0, control voltage on pin VCD or VCG is forced to V_{SS} .

time



7.7 Considerations for ramp-down

Referring to Fig.5, the i-th code can be programmed to have either the $CODE_{END}$ or $CODE_{START}$ value or any code between, depending on the application preferences. These codes do not produce any power at the output of the PA, as $CODE_{START}$ has been chosen to keep the PA isolation. The proper conclusion of the ramp-down is ensured by choosing $CODE_{END} < CODE_{START}$ so that the discharge of the integration capacitance is controlled until the control voltage on pin VCD or VCG goes below the PA conduction threshold and by applying at this time the PU transition from logic 1 to logic 0.

At the beginning of a burst, the VDAC signal steps applied at OP1 are not compensated by any signal at the sensor input up to when pin VCD or VCG voltage is greater than the PA conduction threshold voltage. In any case, the initial DAC voltage steps are stored in the capacitance of amplifier OP1. $CODE_{END}$ has to be chosen so that the energy inside the shaded zone cancels the energy accumulated in the summing node (OP1) at the start of a burst and not balanced by a feedback signal at the sensor input.

The exact value of the energy required depends on the specific PA, on the characteristics of the overall loop and on the values chosen for the settable parameters inside the loop.

A rough idea can be derived with a simplified analysis of a ramp-up, ramp-down cycle using the following simplifications:

- The starting conditions for OP1 and OP4 are biasing at V_{home} with zero charge on capacitances
- The initial rising of pin VCD or VCG voltage from V_{home} is caused only by the integration of the constant CODE_{KICK}
- VDAC is treated as applied directly at the summing node, initially neglecting the transmission delay through the internal low-pass filter.

Generally, the integrator OP4 input can be expressed as

$$V_{in(integrator)} = g_s \times \Delta V_s - g_d \times \Delta V_{VDAC}$$
(1)

where g_s and g_d are respectively the gains of sensor input and DAC input in the summing amplifier OP1.

Equation (1) holds for closed loop operation. In the time interval between the rising of pin VCD or VCG voltage due to CODE_{KICK} (t = 0) and when V_{conduction} for the PA is reached (t = t₁), ΔV_s is 0 and operation is open loop. In this time interval, a charge accumulates in the summing node, which remains uncompensated.

PCF5079

Time t_1 can be calculated with the preceding simplification. Now, to define the quantity

$$\Delta V_{\text{KICK}} = \text{CODE}_{\text{KICK}} - \text{CODE}_{\text{START}}$$
(2)

the current/voltage equations around the integrator OP4 can be solved by forcing the current through R1 to be equal to the current through the integration capacitance and calculating the ΔV generated on C_{INT}, then

$$\Delta V_{CINT} = \frac{1}{C_{CINT}} \times \int_0^t i(\tau) d\tau$$
(3)

where

$$i(\tau) = \frac{g_d \times \Delta V_{KICK}}{R1}$$
(4)

Substituting equation (4) into equation (3)

$$\Delta V_{CINT} = \frac{1}{C_{CINT} \times R1} \times \int_0^t g_d \times \Delta V_{KICK} d\tau$$
(5)

Under the hypothesis the voltage is constant:

$$\Delta V_{CINT} = \frac{1}{C_{CINT} \times R1} \times g_d \times \Delta V_{KICK} \times t$$
(6)

Equation (6) can be used to calculate time t_1 at which the conduction of the PA is reached, considering that

$$t = t_1 \Rightarrow V_{home} + \Delta V_{CINT} = V_{conduction}$$
 (7)

$$t_{1} = R1 \times C_{CINT} \times \frac{V_{conduction} - V_{home}}{g_{d} \times \Delta V_{KICK}}$$
(8)

Time t_1 depends on the time constant of the integrator, by the PA and by ΔV_{KICK} . The condition to be fulfilled is that the energy contained in the shaded zone (Fig.5) is at least equal to the energy accumulated at the beginning:

$$\int_{0}^{t_{1}} V_{out_{OP1}}^{2} (t) dt = k \times QB \times (CODE_{END} - CODE_{START})^{2} (9)$$

where k is the number of quarter-bits during which $CODE_{END}$ is applied.

7.8 Configurations

Table 1 Operating conditions

POWER-UP INPUT (PU)	OPERATING MODE
0	disabled; reset
1	enabled

Table 2 Band selection configuration

BAND SELECT INPUT (BS) ⁽¹⁾	BAND	DRIVER	SWITCHES	CONTROL VOLTAGE
0	GSM	$\begin{array}{l} OP4G \rightarrow active;\\ OP4D \rightarrow power\text{-}down \end{array}$	$\begin{array}{l} SF_G \rightarrow working; \\ SF_D \rightarrow open \end{array}$	$\begin{array}{l} V_{VCG} \rightarrow \text{working}; \\ V_{VCD} \rightarrow V_{SS} \end{array} \label{eq:VCD}$
1	DCS	$OP4D \rightarrow active;$ $OP4G \rightarrow power-down$	$\begin{array}{l} SF_D \rightarrow working; \\ SF_G \rightarrow open \end{array}$	$\begin{array}{l} V_{VCD} \rightarrow \text{working}; \\ V_{VCG} \rightarrow V_{SS} \end{array} \label{eq:VCD}$

Note

1. BS input has to be set before the PU transition logic 0 to logic 1.

7.9 Summary of current and voltage definitions

Refer to Figs 1, 4 and 12.

SYMBOL	DESCRIPTION
V _{VS1}	sensor signal of incident RF power or power sensor 1 signal
V _{VS2}	sensor signal of reflected RF wave or power sensor 2 signal
V _{VDAC}	DAC voltage
V _{VCG}	control voltage of PA
V _{VCD}	control voltage of PA
V _{home}	home position voltage
V _{prebias}	prebias reference voltage; used at the start-up
I _{bias1}	bias current for detector diode D1
I _{bias2}	bias current for detector diode D2
RF _{in}	input signal to the power amplifier
RF _{out}	output signal from the power amplifier

7.10 Timing

Refer to Figs 4 and 5.

SYMBOL	DEFINITION	MIN.	MAX.	UNIT
t _{d1}	delay time; V_{DD} application to PU input transition logic 0 to 1	5.0	_	μs
t _{d2}	delay time; PU input transition logic 0 to 1 to V_{VDAC} ramp-up	20	_	μs
t _{d3}	V _{VDAC} ramp-up detection time	_	3.0	μs
t _{d4}	delay time; ramp-up detected to V_{VCD} , $V_{VCG} = V_{home}$	_	2.6	μs
t _{d5}	delay time; PU input transition logic 1 to 0 to end of burst	_	1.0	μs

PCF5079

8 LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DD}	supply voltage		2.5	+6.0	V
VI	DC input voltage on all pins except VS1 and VS2		-0.5	V _{DD} + 0.5	V
V _{VS1} , V _{VS2}	DC input voltage on pins VS1 and VS2		-3.0	V _{DD} + 0.5	V
li –	DC current into any signal pin		-10	+10	mA
P _{tot}	total power dissipation				
	TSSOP10 package		-	315 ⁽¹⁾	mW
	HVSON10 package		-	844 ⁽²⁾	mW
V _{es}	electrostatic handling voltage	human body model; note 3	2000	-	V
		machine model; note 4			
		pins 4 and 5	150	_	V
		all other pins	200	_	V
T _{stg}	storage temperature		-65	+150	°C
T _{amb}	ambient temperature		-40	+85	°C

Notes

1. Where $P_{tot} = \frac{T_j - T_{amb}}{R_{th(j-a)}}$ and the thermal resistance between junction and ambient $R_{th(j-a)} = 206.3$ K/W.

2. Where $R_{th(j-a)} = 77$ K/W on JEDEC 2S2P board (100 × 100 mm).

3. Human body model: C = 100 pF; R = 1.5 k Ω .

4. Machine model: C = 200 pF; L = 0.75 μ H; R = 0 Ω .

9 ELECTROSTATIC DISCHARGE (ESD)

The PCF5079 is compliant to the General Quality Specification for integrated circuits *"SNW-FQ-611D"* under the stress condition EDSH (human body) and the stress condition ESDM (machine model).

10 DC CHARACTERISTICS

 V_{DD} = 2.5 to 5 V; T_{amb} = -40 to +85 °C; unless otherwise specified.

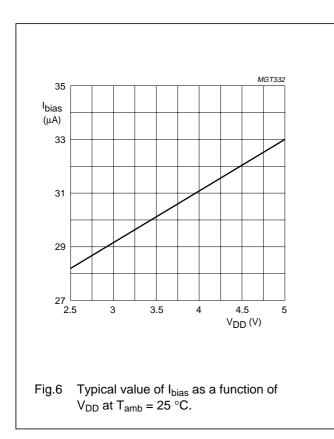
SYMBOL	PARAMETER	CONDITION	MIN.	TYP.	MAX.	UNIT
Supply		•	•	•	•	
V _{DD}	supply voltage		2.5	3.6	5.0	V
I _{DD(op)}	total operating current	no load on pins VCD or VCG	-	-	10	mA
I _{DD(idle)}	total idle current	no load on pins VCD or VCG; note 1	-	_	10	μA
Logic inpu	uts (pins PU and BS)			•		
VIL	LOW-level input voltage		0	-	0.3	V
V _{IH}	HIGH-level input voltage	V _{DD} = 2.5 to 3.7 V	0.9	-	V _{DD}	V
		V _{DD} = 3.7 to 5.0 V	0.95	-	V _{DD}	V
ILL	LOW-level input leakage current	$V_{IL} = 0 V$	-5	_	+5	μA

PCF5079

SYMBOL	PARAMETER	CONDITION	MIN.	TYP.	MAX.	UNIT
I _{LH}	HIGH-level input leakage current	V _{IH} = 5.0 V	-5	-	+5	μA
CI	input capacitance		-	10	-	pF
Sensor in	puts and bias current source (pins	VS1 and VS2)				
V _{VS2}	input voltage		-3	-	V _{DD}	V
V _{VS1}	input voltage		-3	-	V _{DD}	V
I _{bias1} ,	bias current source for detector	V _I = 0 V; T _{amb} = 25 °C; see Fig.6				
I _{bias2}	diodes D1 and D2	$V_{DD} = 2.5 V$	17	28	39	μA
		$V_{DD} = 5.0 V$	21	33	45	μA
TC _{Ibias1} , TC _{Ibias2}	temperature coefficient of I _{bias1} and I _{bias2}		-	0.07	-	mA/K
Internal h	ome position voltage					
V _{home}	internal home position voltage	T _{amb} = 25 °C	0.550	0.600	0.650	V
TC _{Vhome}	temperature coefficient for V _{home}		-	-2.1	-	mV/K

Note

1. A resistive load on pins VCD or VCG to ground (V_{SS}) does not result in additional current consumption.



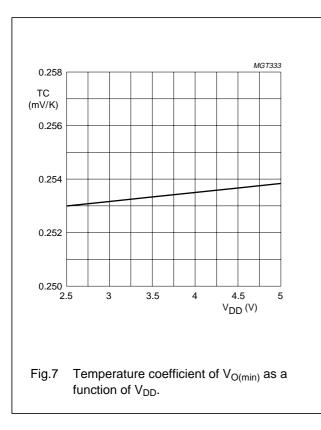
11 OPERATING CHARACTERISTICS

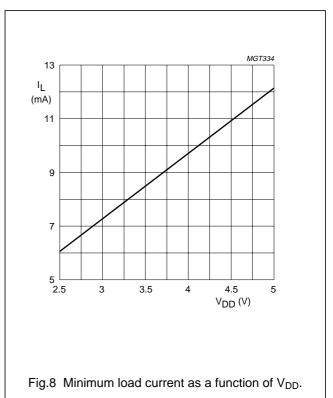
 V_{DD} = 2.5 to 5 V; T_{amb} = –40 to +85 °C; unless otherwise specified.

SYMBOL	PARAMETER	CONDITION	MIN.	TYP.	MAX.	UNIT		
Integrator	(OP4G and OP4D)		•					
V _{DD}	supply voltage		2.5	3.6	5.0	V		
B _G	gain bandwidth	C _L = 120 pF; note 1	-	4	-	MHz		
PSRR	power supply ripple rejection	f = 217 Hz; V _{DD} = 3 V; note 1	50	55	-	dB		
SR _{pos}	positive slew rate	V _{DD} = 3 V; note 2	2.0	3.2	-	V/µs		
SR _{neg}	negative slew rate	V _{DD} = 3 V; note 2	2.0	3.2	-	V/µs		
V _{O(min)}	minimum output voltage	T _{amb} = 25 °C; see Fig.7	-	_	0.2	V		
V _{O(max)}	maximum output voltage	$R_L = 350 \Omega$; see Fig.8	$0.85V_{DD}$	_	-	V		
Capacitor	s C1, C2 and C4							
М	matching ratio accuracy between C1, C2 and C4		_	1	-	%		
Low-pass	Low-pass filter for DAC signal (3rd-order Bessel filter)							
f _{3dB}	corner frequency		70	100	130	kHz		
t _{d(group)}	group delay time	see Fig.11	1.8	3.0	4.2	μs		

Notes

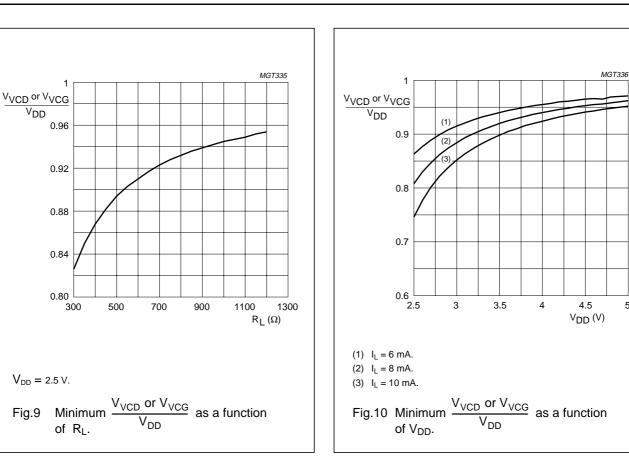
- 1. Guaranteed by design.
- 2. Slew rates are measured between 10% and 90% of output voltage interval with a load of 40 pF to ground.

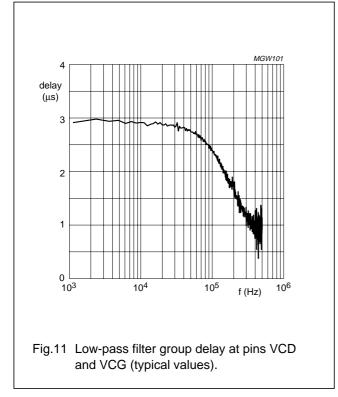




V_{DD}

Dual-band power amplifier controller for GSM, PCN and DCS





PCF5079

5

12 APPLICATION INFORMATION

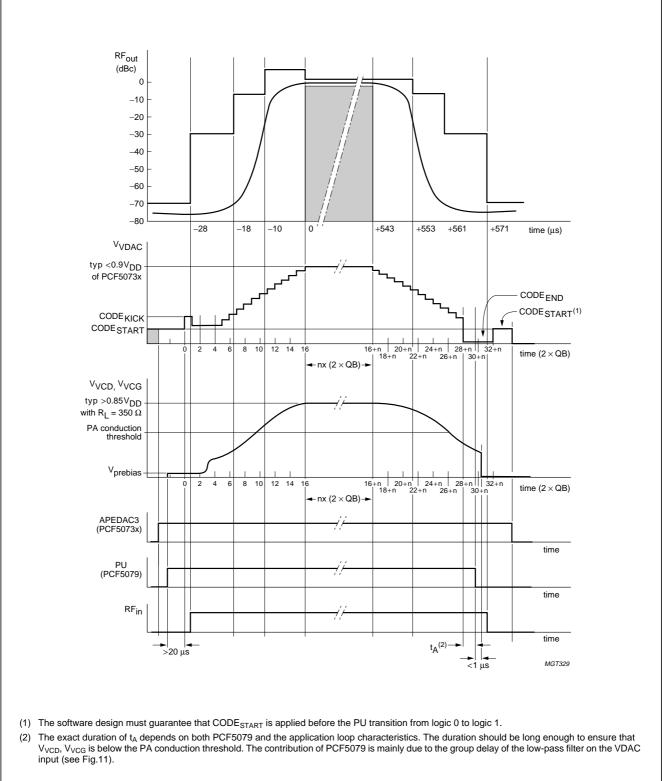
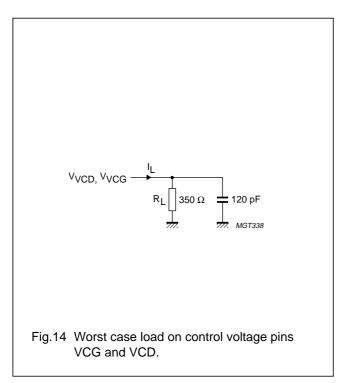


Fig.12 Timing diagram for one time slot with PCF5073x family.

RE SECTION VCG VDD 10 CINT1 < 50 pF VINT(N) BS R1 R2 2 c 1 kΩ 1 kΩ CINT2 < 50 pF VCD PU PCF5079 3 8 VS1 VDAC 7 ____ 0 to 2.3 V Vss VS2 5 6 AUXDAC3 PCF5073x MGT337 Fig.13 Diagram showing external components required.



12.1 Ramp control

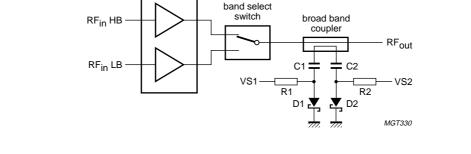
$$\begin{split} & \text{CODE}_{\text{KICK}} \text{ and } V_{\text{home}} \text{ define the starting conditions for} \\ & \text{ramping-up. Ramping-up and ramping-down are defined} \\ & \text{by } V_{\text{VDAC}}. \text{ CODE}_{\text{END}} \text{ and } \text{CODE}_{\text{START}} \text{ define the correct} \\ & \text{shut-off of the power module.} \end{split}$$

The non-linear behaviour of the control curves of the power modules has a large influence on the loop. Starting conditions in the flat area of the control curve are critical and need some attention. Initially the voltage on pins VCD (VCG) will be at the home position. Successively, the integrator is moved into the active part of the control curve.

This is achieved by integrating $\text{CODE}_{\text{KICK}}$. When VCD (VCG) voltage has reached the active region of the control curve, the loop is closed and the circuit can follow the ramping function generated at pin VDAC. The top value of VDAC voltage determines the power of the transmit burst. Ramping-down is started according to the decrease of VDAC voltage. The loop follows the leading function for ramping-down until the RF sensor leaves its active region. The reason for CODE_{START} and CODE_{END} is to shorten the tail of the slope.

12.2 PA protection against mismatch

High VSWR at the PA output may occur in systems where the PA is connected to the antenna via couplers and switches with low insertion loss, depending on the antenna matching. The incident and reflected power have to be monitored and care has to be taken to prevent the summed RF power does not exceed the defined maximum value at the PA output. As two sensor inputs are available in the PCF5079, two different detector signals can be combined: one for direct path and one for reflected path. These two voltages, fed to the sensor inputs, are summed inside the PCF5079 resulting in a decrease in the PA output power if there is an increase of the VSWR at the antenna port (see Fig.15).



PA



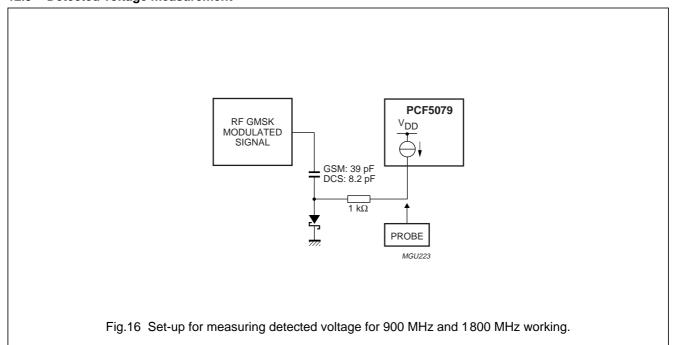
Table 3 Table of components (see Fig.15)

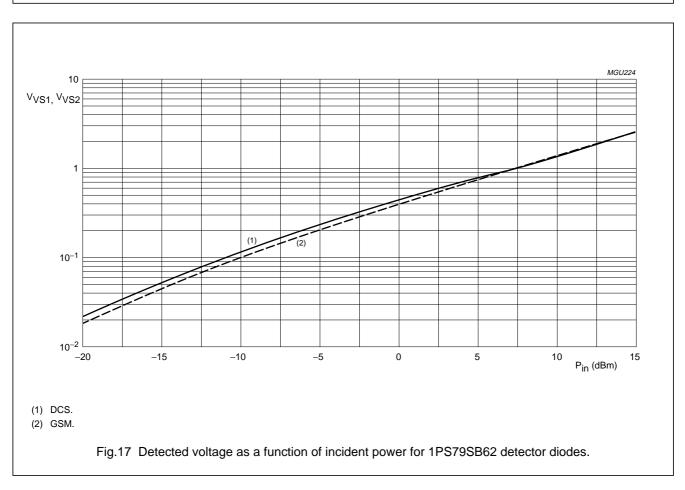
SYMBOL	COMPONENT	DESCRIPTION
D1, D2	detector diode	Philips 1PS79SB62
R1, R2	resistor	$R = 1 k\Omega$ (decoupling versions)
C1, C2	capacitor	C = 39 pF
_	band select switch	Motorola; Alpha Industries; M/A; COM GaAs MMIC; or discrete pin diode, e.g. Philips BAP51-03
_	broad band coupler	Murata LCD20 series; TDK HHM 20, 22 series

PCF5079

Dual-band power amplifier controller for GSM, PCN and DCS

12.3 Detected voltage measurement

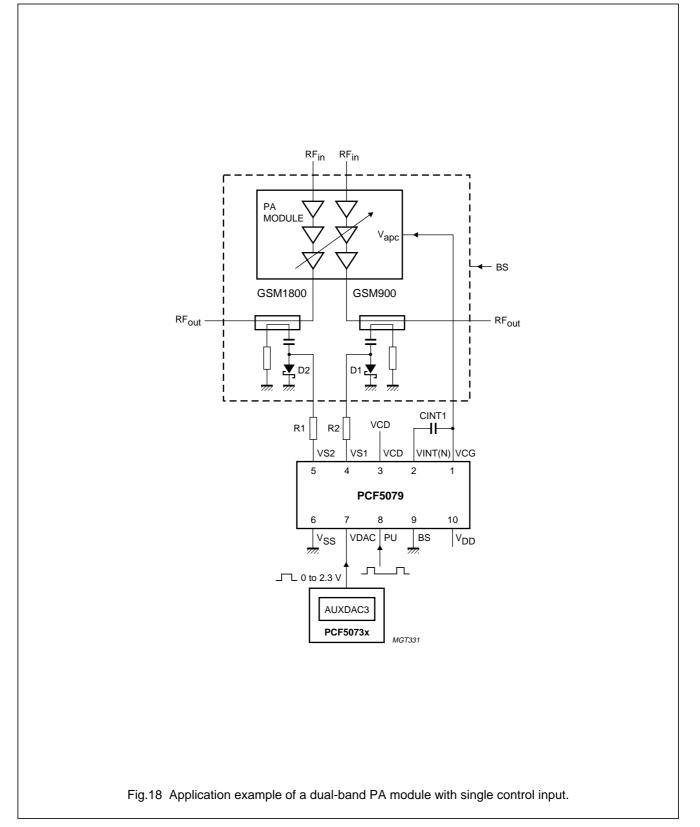




PCF5079

Dual-band power amplifier controller for GSM, PCN and DCS

12.4 Application examples

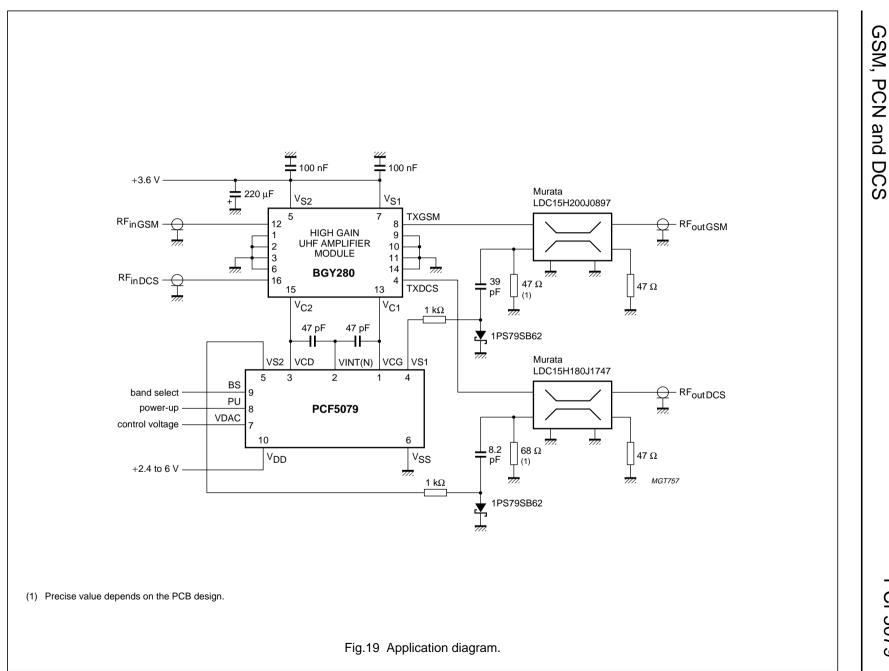


Philips Semiconductors

Product specification

Dual-band power amplifier controller for GSM, PCN and DCS

PCF5079



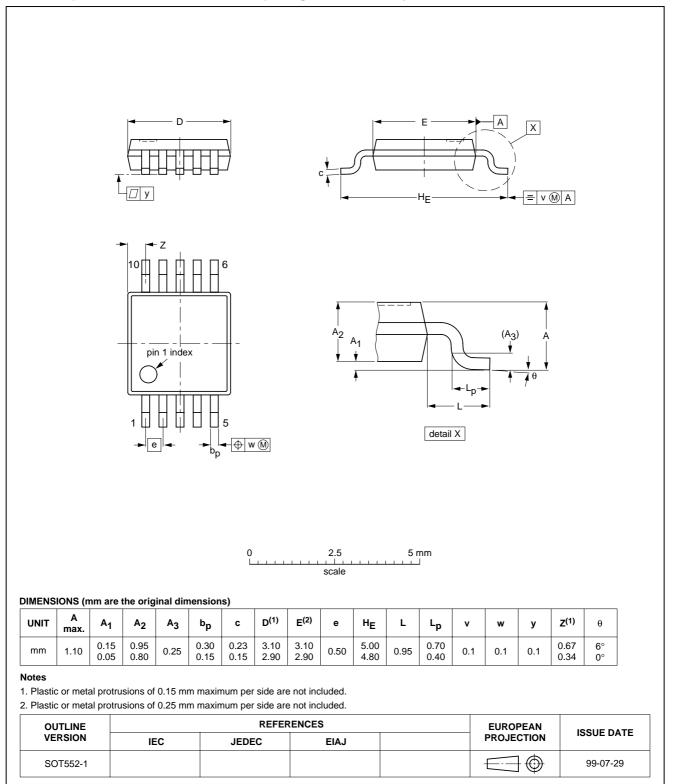
2001 Nov 21

_

20

13 PACKAGE OUTLINES

TSSOP10: plastic thin shrink small outline package; 10 leads; body width 3 mm



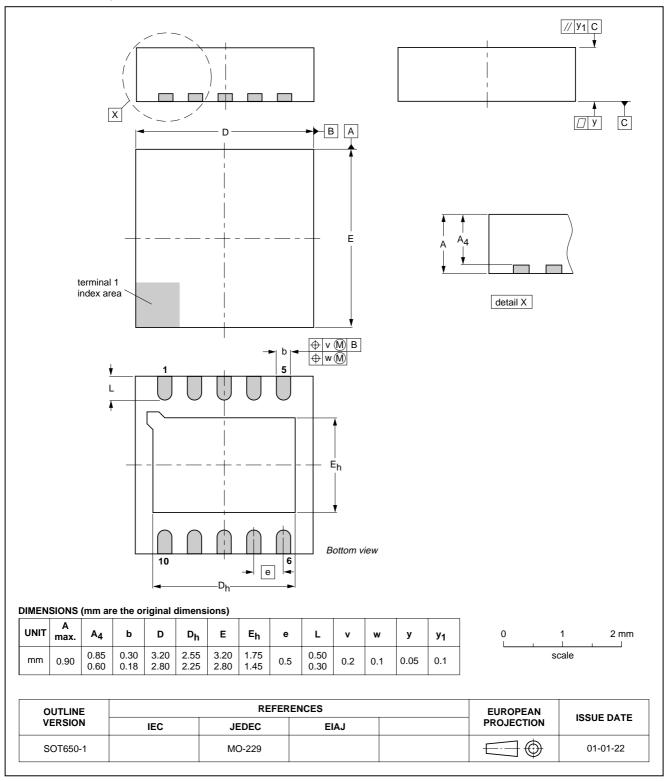
PCF5079

SOT552-1

PCF5079

SOT650-1

HVSON10: plastic, heatsink very thin small outline package; no leads; 10 terminals; body 3 x 3 x 0.90 mm



PCF5079

14 SOLDERING (TSSOP10)

14.1 Introduction to soldering surface mount packages

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *"Data Handbook IC26; Integrated Circuit Packages"* (document order number 9398 652 90011).

There is no soldering method that is ideal for all surface mount IC packages. Wave soldering is not always suitable for surface mount ICs, or for printed-circuit boards with high population densities. In these situations reflow soldering is often used.

14.2 Reflow soldering

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement.

Several methods exist for reflowing; for example, infrared/convection heating in a conveyor type oven. Throughput times (preheating, soldering and cooling) vary between 100 and 200 seconds depending on heating method.

Typical reflow peak temperatures range from 215 to 250 °C. The top-surface temperature of the packages should preferable be kept below 230 °C.

14.3 Wave soldering

Conventional single wave soldering is not recommended for surface mount devices (SMDs) or printed-circuit boards with a high component density, as solder bridging and non-wetting can present major problems.

To overcome these problems the double-wave soldering method was specifically developed.

If wave soldering is used the following conditions must be observed for optimal results:

- Use a double-wave soldering method comprising a turbulent wave with high upward pressure followed by a smooth laminar wave.
- For packages with leads on two sides and a pitch (e):
 - larger than or equal to 1.27 mm, the footprint longitudinal axis is preferred to be parallel to the transport direction of the printed-circuit board;
 - smaller than 1.27 mm, the footprint longitudinal axis must be parallel to the transport direction of the printed-circuit board.

The footprint must incorporate solder thieves at the downstream end.

• For packages with leads on four sides, the footprint must be placed at a 45° angle to the transport direction of the printed-circuit board. The footprint must incorporate solder thieves downstream and at the side corners.

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Typical dwell time is 4 seconds at 250 °C. A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

14.4 Manual soldering

Fix the component by first soldering two diagonally-opposite end leads. Use a low voltage (24 V or less) soldering iron applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300 °C.

When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds between 270 and 320 $^\circ\text{C}.$

PCF5079

14.5 Suitability of surface mount IC packages for wave and reflow soldering methods

PACKAGE	SOLDERING METHOD	
FACKAGE	WAVE	REFLOW ⁽¹⁾
BGA, LFBGA, SQFP, TFBGA	not suitable	suitable
HBCC, HLQFP, HSQFP, HSOP, HTQFP, HTSSOP, SMS	not suitable ⁽²⁾	suitable
PLCC ⁽³⁾ , SO, SOJ	suitable	suitable
LQFP, QFP, TQFP	not recommended ⁽³⁾⁽⁴⁾	suitable
SSOP, TSSOP, VSO	not recommended ⁽⁵⁾	suitable

Notes

- 1. All surface mount (SMD) packages are moisture sensitive. Depending upon the moisture content, the maximum temperature (with respect to time) and body size of the package, there is a risk that internal or external package cracks may occur due to vaporization of the moisture in them (the so called popcorn effect). For details, refer to the Drypack information in the "Data Handbook IC26; Integrated Circuit Packages; Section: Packing Methods".
- 2. These packages are not suitable for wave soldering as a solder joint between the printed-circuit board and heatsink (at bottom version) can not be achieved, and as solder may stick to the heatsink (on top version).
- 3. If wave soldering is considered, then the package must be placed at a 45° angle to the solder wave direction. The package footprint must incorporate solder thieves downstream and at the side corners.
- 4. Wave soldering is only suitable for LQFP, TQFP and QFP packages with a pitch (e) equal to or larger than 0.8 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.65 mm.
- 5. Wave soldering is only suitable for SSOP and TSSOP packages with a pitch (e) equal to or larger than 0.65 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.5 mm.

Product specification

Dual-band power amplifier controller for GSM, PCN and DCS

15 SOLDERING (HVSON10)

15.1 Soldering information

Information contained within this chapter is of a preliminary nature and may change without notice.

15.2 PCB design guidelines

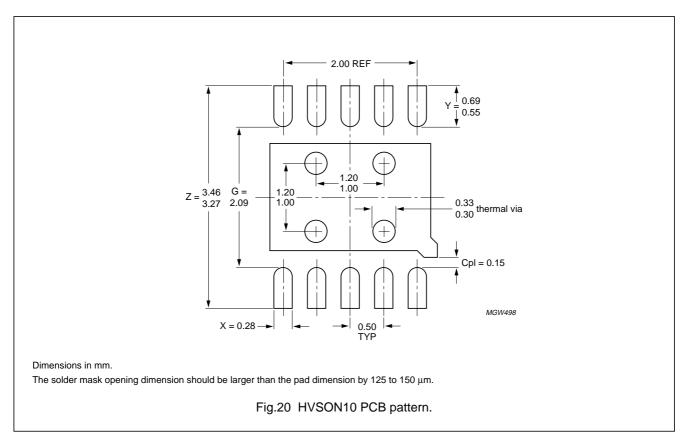
These guidelines are to help the user in developing the proper PCB design. For the surface mount process refer to *"Data Handbook IC26; Integrated Circuit Packages"* (document order number 9398 652 90011).

15.2.1 PERIMETER PAD DESIGN

Referring to Fig.20, dimensions Z and G are respectively the outside to outside and the inside to inside pad dimensions.

The dimensions X and Y indicate respectively the width and the length of the pad. Note that the calculated X dimension is the maximum value in order to avoid solder bridging between adjacent pads.The calculated Y dimension is the minimum value and therefore pad design should start with this value and the pad length at the outside be extended if more solder joint fillets are required.

The dimension 'Cpl' defines the minimum distance between the inner tip of the pad and the outer edge of the thermal pad. It is suggested that this dimension be fixed at 0.15 mm to avoid solder bridging issues between the thermal pad and the perimeter pads.



15.2.2 THERMAL PAD AND VIA DESIGN

The size of the thermal pad should at least match the size of the exposed die-attach paddle. However, in some cases, the die-attach paddle size may need to be modified to avoid solder bridging between the thermal pad and the perimeter pads. In order to effectively transfer heat from the top metal layer to the inner or bottom layers of the PCB, thermal vias should be incorporated into the thermal pad design. The number of thermal vias will depend on the application and on the power dissipation and electrical requirements. It is recommended to incorporate an array of thermal vias at a pitch of 1.0 to 1.2 mm with the via diameter between 0.3 and 0.33 mm.

15.2.3 STENCIL DESIGN FOR PERIMETER PADS

For optimum paste release the area and aspect ratios of the stencil should be greater than 0.66 and 1.5 respectively.

Area ratio =
$$\frac{\text{area of aperture opening}}{\text{aperture wall area}} = \frac{L \times W}{2T(L + W)}$$

Aspect ratio = $\frac{\text{aperture width}}{\text{stencil thickness}} = \frac{W}{T}$

where:

L = aperture length

W = aperture width

T = stencil thickness.

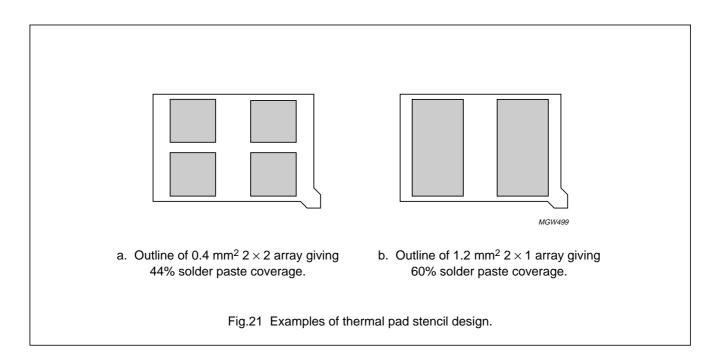
15.2.4 STENCIL DESIGN FOR THERMAL PADS

In order to remove the heat effectively from the package and to enhance electrical performance the die-attach paddle needs to be soldered to the PCB thermal pad, preferably with minimum voids.

It is therefore recommended that smaller, multiple openings in a stencil should be used instead of one large opening for printing solder paste in the thermal pad region. This results typically in 50% to 80% solder paste coverage. Two examples are shown in Fig.21.

15.2.5 STENCIL THICKNESS

A stencil thickness of 0.125 to 0.150 mm is recommended but this value needs to be optimized by the user to find the proper thickness according to application requirements.



PCF5079

16 DATA SHEET STATUS

DATA SHEET STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITIONS
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Changes will be communicated according to the Customer Product/Process Change Notification (CPCN) procedure SNW-SQ-650A.

Notes

- 1. Please consult the most recently issued data sheet before initiating or completing a design.
- 2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.

17 DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information — Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors make no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

18 DISCLAIMERS

Life support applications — These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips Semiconductors customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips Semiconductors for any damages resulting from such application.

Right to make changes — Philips Semiconductors reserves the right to make changes, without notice, in the products, including circuits, standard cells, and/or software, described or contained herein in order to improve design and/or performance. Philips Semiconductors assumes no responsibility or liability for the use of any of these products, conveys no licence or title under any patent, copyright, or mask work right to these products, and makes no representations or warranties that these products are free from patent, copyright, or mask work right infringement, unless otherwise specified.

Philips Semiconductors – a worldwide company

Contact information

For additional information please visit http://www.semiconductors.philips.com. Fax: +31 40 27 24825 For sales offices addresses send e-mail to: sales.addresses@www.semiconductors.philips.com.

© Koninklijke Philips Electronics N.V. 2001

All rights are reserved. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner.

The information presented in this document does not form part of any quotation or contract, is believed to be accurate and reliable and may be changed without notice. No liability will be accepted by the publisher for any consequence of its use. Publication thereof does not convey nor imply any license under patent- or other industrial or intellectual property rights.

Printed in The Netherlands

403506/01/pp28

Date of release: 2001 Nov 21

Document order number: 9397 750 07095

SCA73

Let's make things better.





Philips Semiconductors